



Date Created: 3/29/2004
Date Issued: 4/6/2004
PCN # 20041001-A

DESIGN/PROCESS CHANGE NOTIFICATION -- FINAL

Reference FCST PCN number 20030402-A.

This is to inform you that a design and/or process change will be made to the following product(s). This notification is for your information and concurrence.

If you require data or samples to qualify this change, please contact **Fairchild Semiconductor within 30 days of receipt of this notification.**

If you have any questions concerning this change, please contact:

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Phone: 1-408-822-2143

PCN Originator

Name: Knapp, Paul E.
E-mail: Paul.Knapp@notes.fairchildsemi.com
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REL Engineer

Name: Chamberlin, Clint
E-mail: Clint.Chamberlin@notes.fairchildsemi.com
Phone: 570-474-3240

PCN Type: Alternate Fab Location

Effectivity

Expected 1st Device Shipment Date: 4/23/2004
Earliest Year/Work Week of Changed Product: 0417
(Note: Package marking may differ from this format)

Product ID (Description):

This change affects certain products that were run on our 6-inch wafer fab line in Mountain Top, PA. The products affected by this change are listed below in the "Affected FSIDs" section.

Description of Change:

The Fairchild Mountain Top 6-inch fab line has been closed. The Mountain Top 8-inch fab line will continue to remain open. The products are identified in the attached "Affected FSIDs" list, will be transferred to our QS 9000 approved Bucheon, Korea facility for wafer fabrication.

Mountaintop, Pennsylvania and Bucheon, South Korea Fairchild Semiconductor address:

Fairchild Semiconductor
(420-711) 82-3 Todang-Dong
Wonmi-District
Bucheon City, Kyonggi Province
Korea

Fairchild Semiconductor
 Crestwood Industrial Park
 125 Crestwood Road
 Mountain Top, PA 18707

Effect of Change:

The change in wafer fabrication site has no effect on device specifications, function, or reliability. The transfer of wafer fabrication of these devices to another QS9000 approved wafer fab site will have no effect on device specifications, performance, function, quality, or reliability.

Qualification:

Qualification reports follows.

Qual/REL Plan Numbers

Additional Qualification Data

Qual Plan Nbr : **PD03060035**

Title : Qualification of 55-60V UltraFETs from Bucheon 6"

Background/Description : This technology is being transferred from Mtop to Bucheon, using CPM qualified package.

Scope : Applies to all currently qualified 55-60V UltraFETs MOS devices listed in this PCN

ATTACHMENT 1
RELIABILITY TEST RESULT SUMMARY

COMPONENT LEVEL

TEST	CONDITION	REL #	230364 13058/14014	230365 13058/14014	230361 13058/14014	Remarks
		DEVICE	HUF75344P3	HUF75344P3	HUF75344P3	
		CHIP	79344	79344	79344	
		PKG	TO-220	TO-220	TO-220	
		DIE LOT#	GJZAQ GTZ1D	GKZA9 GTZ1E	GJZBK GTZ20	
		DURATION	# OF FAILURES	# OF FAILURES	# OF FAILURES	
Autoclave	12I C, 15 psi	96 hrs	0/77	0/77	0/77	
Temp Cycle	-55°C TO 150°C, 15MIN DWELL	1000cyc	0/77	0/77	0/77	
Hast	130°C/85%RH Vr=80% Bvdss	96hrs	0/77	0/77	0/77	
HTGB	150°C, Vg=100% Vgs	1000hrs	0/77	0/77	0/77	
HTRB	150°C, Vr=80% Bvdss	1000hrs	0/77	0/77	0/77	
Power Cycle	Tj DELTA 100C	10Kcyc	0/77	0/77	0/77	

Affected FSIDs

BUZ11_R4941
HUF75307D3
HUF75307T3_ST136
HUF75309P3
HUF75321D3S
HUF75321S3S
HUF75329D3S
HUF75329P3
HUF75332P3
HUF75333S3
HUF75337S3S
HUF75339S3ST_R4935
HUF75343G3
HUF75343S3S
HUF75344P3
HUF75345P3
HUF75345S3ST
RFD14N05
RFD14N05LSM9A
RFD16N05
RFD16N05SM
RFD3055LE
RFD3055SM
RFG70N06
RFP45N06

HRF3205
HUF75307D3ST
HUF75309D3S
HUF75309T3ST
HUF75321D3ST
HUF75321S3ST_R4908
HUF75329D3ST
HUF75329S3
HUF75332S3ST
HUF75333S3ST
HUF75339G3
HUF75339S3ST_S2550
HUF75343P3
HUF75343S3ST
HUF75344S3ST
HUF75345S3
RF1K49154
RFD14N05L
RFD14N05SM
RFD16N05LSM
RFD16N05SM9A
RFD3055LESM
RFD3055SM9A
RFP3055
RFP50N06

HRFZ44N
HUF75307T3ST
HUF75309D3ST
HUF75321D3
HUF75321P3
HUF75329D3
HUF75329G3
HUF75329S3ST
HUF75333P3
HUF75337P3
HUF75339P3
HUF75339S3ST_S2575
HUF75343S3
HUF75344G3
HUF75345G3
HUF75345S3S
RF1K4915496
RFD14N05LSM
RFD14N05SM9A
RFD16N05LSM9A
RFD3055
RFD3055LESM9A
RFD3055SM9A136
RFP3055LE
RFP70N06